Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	8	((generat$ same program$) near connect$) and (program$ same run$ same together)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 13:27
L2	47	plural$ near (program$ same run$) and (program same generat$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:42
L3	0	717/106.ccls. and (program$ same generat$ same method) and (plural$ same program$) and (navigation$ same program$ same display$) and (generat$ same connect$ same program$) and input$ and (user same authoriz$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:43
L4	31	(program$ same generat$ same method) and (plural$ same program$) and (navigation$ same program$ same display$) and (generat$ same connect$ same program$) and input$ and (user same authoriz$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 13:25
L5	2	"20020087946".PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 13:52
S11	40	plural$ near (program$ same run$) and (program same generat$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:41
S23	27	(program$ same generat$ same method) and (plural$ same program$) and (navigation$ same program$ same display$) and (generat$ same connect$ same program$) and input$ and (user same authoriz$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 13:24
S24	0	717/106.ccls. and (program$ same generat$ same method) and (plural$ same program$) and (navigation$ same program$ same display$) and (generat$ same connect$ same program$) and input$ and (user same authoriz$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:43

Search Result - Print Format

Key: IEEE JNL = IEEE Journal or Magazine, **IEE JNL** = IEE Journal or Magazine, **IEEE CNF** = IEEE Conference, **IEE CNF** = IEE Conference, **IEEE STD** = IEEE Standard

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